

**Search Notes**

Application/Control No.

10/817,095

Examiner

Huy D. Nguyen

Applicant(s)/Patent under  
Reexamination

HWANG ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	560	10/14/2005	HN
	522		
	526		
	3.02		
	418		
	419		
	515		
	434		
	13.4		
	511		
	68		
	70		
Updated	search	11/1/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
455	560	11/1/2006	HN
	434		
	515		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (USPAT, US-PGPUB, JPO, EPO, DERWENT) - See search history printout.	10/14/2005	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT) - See search history printout.	11/1/2006	HN
See interference search printout.	11/1/2006	HN